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AP3 Rec'd PCT/PTO 12 JUN 2006

IN THE UNITED STATES PATENT & TRADEMARK OFFICE

**Applicant:** Christoph Weber, et al.  
**International Application No.:** PCT/EP2005/051746  
**International Filing Date:** 20 April 2005  
**Title:** CORRECTION METHOD FOR CHIP REMOVAL MACHINES  
**Agent's Reference No.:** STT-C-PCT-US  
**Date:** June 12, 2006

BOX PCT  
U.S. Receiving Office  
Commissioner of Patents and Trademarks

**INFORMATION DISCLOSURE STATEMENT**

Sir:

This invention relates to a method for determining a deviation of at least one regulating variable on chip removal machines with a mechanical drive for a tool and/or a workpiece, regulated by a control system, wherein the regulation comprises a plurality of values  $C, X, Z$  of at least three spatial axes  $c, x, z$  for the control system and for the drive, and the values  $C, X, Z$  have a functional relation such as  $Z = f_{bi}(C, X)$  with the axes  $c, x, z$ . A protocol is prepared from a plurality of control system actual values ( $C_{p,s}, X_{p,s}, Z_{p,s}$ ) detected by measuring means and/or selected drive actual values ( $C_{p,a}, X_{p,a}, Z_{p,a}$ ) and a control system nominal value according to  $Z_{bi,s} = f_{bi}(C_{p,s}, X_{p,s})$  and/or a drive nominal value according to  $Z_{bi,a} = f_{bi}(C_{p,a}, X_{p,a})$  is calculated at least in relation to the  $z$ -axis, and a control system differential value according to  $D_{z,s} = Z_{p,s} - Z_{bi,s}$  and/or a drive differential value according to  $D_{z,a} = Z_{p,a} - Z_{bi,a}$  is calculated at least in relation to the  $z$ -axis. The invention also pertains to a chip removal machine which implements such a method.

As authorized and encouraged under 37 C.F.R. §1.97-1.99, applicant hereby cites as a means of complying with the duty of disclosure set forth in 37 C.F.R. §1.56, the following patents and/or documents, required copies enclosed, which the Examiner should consider with respect to the above-identified United States Patent Application:

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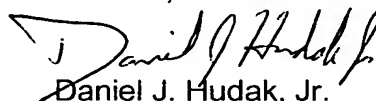
U.S. DOCUMENTS		
PATENT/DOCUMENT NO.	DATE	INVENTOR
3,474,231 (English family of CH 425 958)	10/21/1969	Laube
FOREIGN DOCUMENTS		
PATENT/DOCUMENT NO.	DATE	COUNTRY
425 958	09/15/1957	CH
2 253 014	05/03/1973	DE
25 37 630	03/11/1976	DE
31 51 173	07/14/1983	DE
39 14549	11/09/1990	DE
39 02 840	08/23/1990	DE
44 12 370	10/19/1995	DE
0 854 769	07/29/1998	EP
199 19 147	11/16/2000	DE
02/37168	05/10/2002	WIPO

In accordance with 37 CFR 1.98(a)(2)(i) only the foreign and non-patent documents are required for the express purpose of providing the Patent and Trademark Office with an ample opportunity to evaluate the same and to arrive at an independent assessment of its materiality, if any, with regard to the examination of the application.

An examination of the present application considering the above documents is requested.

Respectfully submitted,

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Attorney Docket No.: STT-C-PCT-US

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<b>Form PTO-1449</b> U.S. Department of Commerce Patent and Trademark Office  <b>LIST OF PRIOR ART CITED BY APPLICANT</b> (Use several sheets if necessary)		Atty. Docket No.: STT-C-PCT-US Applicant: Christoph Weber, et al. Filing Date: 06/12/2006		Serial No.:  Group:			
<b>U.S. PATENT DOCUMENTS</b>							
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing date if appropriate
	AA	3,474,231	10/21/1969	Laube			
	AB						
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	AG						
	AH						
	AI						
	AJ						
	AK						
<b>FOREIGN PATENT DOCUMENTS</b>							
		Document Number	Date	Country	Class	Subclass	Translation Yes No
	AL	425 958	09/15/1957	CH			
	AM	2 253 014	05/03/1973	DE			
	AN	25 37 630	03/11/1976	DE			
	AO	31 51 173	07/14/1983	DE			
	AP	39 14549	11/09/1990	DE			
<b>OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)</b>							
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	AT						
EXAMINER				DATE CONSIDERED			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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<b>U.S. PATENT DOCUMENTS</b>							
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